

SVENSK STANDARD

SS-EN 15063-1:2014



Fastställt/Approved: 2014-12-21
Publicerad/Published: 2015-01-12
Utgåva/Edition: 2
Språk/Language: engelska/English
ICS: 77.040.20; 77.120.30

Koppar och kopparlegeringar – Bestämning av huvudbeståndsdelar och orenheter genom våglängdsskingrande röntgenfluorescencespektrometri (XRF) – Del 1: Riktlinjer för rutinmetod

Copper and copper alloys – Determination of main constituents and impurities by wavelength dispersive X-ray fluorescence spectrometry (XRF) – Part 1: Guidelines to the routine method



Standarder får världen att fungera

SIS (Swedish Standards Institute) är en fristående ideell förening med medlemmar från både privat och offentlig sektor. Vi är en del av det europeiska och globala nätverk som utarbetar internationella standarder. Standarder är dokumenterad kunskap utvecklad av framstående aktörer inom industri, näringsliv och samhälle och befrämjar handel över gränser, bidrar till att processer och produkter blir säkrare samt effektiviserar din verksamhet.

Delta och påverka

Som medlem i SIS har du möjlighet att påverka framtida standarder inom ditt område på nationell, europeisk och global nivå. Du får samtidigt tillgång till tidig information om utvecklingen inom din bransch.

Ta del av det färdiga arbetet

Vi erbjuder våra kunder allt som rör standarder och deras tillämpning. Hos oss kan du köpa alla publikationer du behöver – allt från enskilda standarder, tekniska rapporter och standardpaket till handböcker och onlinetjänster. Genom vår webbtjänst e-nav får du tillgång till ett lättnavigerat bibliotek där alla standarder som är aktuella för ditt företag finns tillgängliga. Standarder och handböcker är källor till kunskap. Vi säljer dem.

Utveckla din kompetens och lyckas bättre i ditt arbete

Hos SIS kan du gå öppna eller företagsinterna utbildningar kring innehåll och tillämpning av standarder. Genom vår närhet till den internationella utvecklingen och ISO får du rätt kunskap i rätt tid, direkt från källan. Med vår kunskap om standarders möjligheter hjälper vi våra kunder att skapa verklig nytta och lönsamhet i sina verksamheter.

Vill du veta mer om SIS eller hur standarder kan effektivisera din verksamhet är du välkommen in på www.sis.se eller ta kontakt med oss på tel 08-555 523 00.



Standards make the world go round

SIS (Swedish Standards Institute) is an independent non-profit organisation with members from both the private and public sectors. We are part of the European and global network that draws up international standards. Standards consist of documented knowledge developed by prominent actors within the industry, business world and society. They promote cross-border trade, they help to make processes and products safer and they streamline your organisation.

Take part and have influence

As a member of SIS you will have the possibility to participate in standardization activities on national, European and global level. The membership in SIS will give you the opportunity to influence future standards and gain access to early stage information about developments within your field.

Get to know the finished work

We offer our customers everything in connection with standards and their application. You can purchase all the publications you need from us - everything from individual standards, technical reports and standard packages through to manuals and online services. Our web service e-nav gives you access to an easy-to-navigate library where all standards that are relevant to your company are available. Standards and manuals are sources of knowledge. We sell them.

Increase understanding and improve perception

With SIS you can undergo either shared or in-house training in the content and application of standards. Thanks to our proximity to international development and ISO you receive the right knowledge at the right time, direct from the source. With our knowledge about the potential of standards, we assist our customers in creating tangible benefit and profitability in their organisations.

If you want to know more about SIS, or how standards can streamline your organisation, please visit www.sis.se or contact us on phone +46 (0)8-555 523 00



Europastandarden EN 15063-1:2014 gäller som svensk standard. Detta dokument innehåller den officiella engelska versionen av EN 15063-1:2014.

Denna standard ersätter SS-EN 15063-1:2006, utgåva 1.

The European Standard EN 15063-1:2014 has the status of a Swedish Standard. This document contains the official version of EN 15063-1:2014.

This standard supersedes the Swedish Standard SS-EN 15063-1:2006, edition 1.

© Copyright/Upphovsrätten till denna produkt tillhör SIS, Swedish Standards Institute, Stockholm, Sverige. Användningen av denna produkt regleras av slutanvändarlicensen som återfinns i denna produkt, se standardens sista sidor.

© Copyright SIS, Swedish Standards Institute, Stockholm, Sweden. All rights reserved. The use of this product is governed by the end-user licence for this product. You will find the licence in the end of this document.

Upplysningar om sakinnehållet i standarden lämnas av SIS, Swedish Standards Institute, telefon 08-555 520 00. Standarder kan beställas hos SIS Förlag AB som även lämnar allmänna upplysningar om svensk och utländsk standard.

Information about the content of the standard is available from the Swedish Standards Institute (SIS), telephone +46 8 555 520 00. Standards may be ordered from SIS Förlag AB, who can also provide general information about Swedish and foreign standards.

Denna standard är framtagen av kommittén för Koppar, SIS/TK 132.

Har du synpunkter på innehållet i den här standarden, vill du delta i ett kommande revideringsarbete eller vara med och ta fram andra standarder inom området? Gå in på www.sis.se - där hittar du mer information.

EUROPEAN STANDARD

EN 15063-1

NORME EUROPÉENNE

EUROPÄISCHE NORM

December 2014

ICS 77.040.20; 77.120.30

Supersedes EN 15063-1:2006

English Version

Copper and copper alloys - Determination of main constituents and impurities by wavelength dispersive X-ray fluorescence spectrometry (XRF) - Part 1: Guidelines to the routine method

Cuivre et alliages de cuivre - Détermination des éléments principaux et des impuretés par spectrométrie de fluorescence X à dispersion de longueur d'onde (FRX) - Partie 1 : Lignes directrices pour la méthode de routine

Kupfer und Kupferlegierungen - Bestimmung von Hauptbestandteilen und Verunreinigungen durch wellenlängendispersive Röntgenfluoreszenzanalyse (RFA) - Teil 1: Leitfaden für das Routineverfahren

This European Standard was approved by CEN on 8 November 2014.

CEN members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration. Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CEN member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CEN member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CEN members are the national standards bodies of Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and United Kingdom.



EUROPEAN COMMITTEE FOR STANDARDIZATION
COMITÉ EUROPÉEN DE NORMALISATION
EUROPÄISCHES KOMITEE FÜR NORMUNG

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

Contents	Page
Foreword.....	3
Introduction	4
1 Scope	5
2 Principle.....	5
3 Terms and definitions	5
4 Instrumentation.....	7
4.1 Principles of X-ray fluorescence spectrometers	7
4.2 X-ray tubes	8
4.3 Vacuum system.....	9
4.4 Test sample spinner	9
4.5 Filters	9
4.6 Collimators of slits.....	10
4.7 Analysing crystals	10
4.8 Counters	11
4.9 Simultaneous and sequential Instruments	12
5 Sampling and test sample preparation	12
6 Evaluation methods.....	12
6.1 General.....	12
6.2 Dead time correction	12
6.3 Background correction	13
6.4 Line interference correction models.....	13
6.5 Inter-element effects correction models	13
7 Calibration procedure	14
7.1 General.....	14
7.2 Optimizing of the diffraction angle (2θ).....	15
7.3 Selecting optimum conditions for detectors	15
7.4 Selecting optimum tube voltage and current	15
7.5 Selecting minimum measuring times	15
7.6 Selecting calibration samples	15
7.7 Selecting drift control and recalibration samples	16
7.8 Measuring the calibration samples.....	16
7.9 Regression calculations	16
8 Method validation (accuracy and precision).....	16
9 Performance criteria.....	17
9.1 General.....	17
9.2 Precision test	17
9.3 Performance monitoring	17
9.4 Maintenance	17
10 Radiation protection.....	18
Annex A (informative) Example of calculating background equivalent concentration, limit of detection, limit of quantification and lower limit of detection	19
Annex B (informative) Example of calculating line interference of one element to another	21
Annex C (informative) Example of performance criteria obtained under repeatability conditions	22
Bibliography.....	23

Foreword

This document (EN 15063-1:2014) has been prepared by Technical Committee CEN/TC 133 “Copper and copper alloys”, the secretariat of which is held by DIN.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by June 2015 and conflicting national standards shall be withdrawn at the latest by June 2015.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN [and/or CENELEC] shall not be held responsible for identifying any or all such patent rights.

This document supersedes EN 15063-1:2006.

Within its programme of work, Technical Committee CEN/TC 133 requested CEN/TC 133/WG 10 “Methods of analysis” to revise the following standard:

EN 15063-1:2006, *Copper and copper alloys — Determination of main constituents and impurities by wavelength dispersive X-ray fluorescence spectrometry (XRF) — Part 1: Guidelines to the routine method*

This is one of two parts of the standard for the determination of main constituents and impurities in copper and copper alloys. The other part is:

EN 15063-2, *Copper and copper alloys — Determination of main constituents and impurities by wavelength dispersive X-ray fluorescence spectrometry (XRF) — Part 2: Routine method*

In comparison with EN 15063-1:2006, the following changes have been made:

- a) Definition 3.1 and 3.2 modified;
- b) Clause 5 modified;
- c) Editorial modifications have been made.

According to the CEN-CENELEC Internal Regulations, the national standards organizations of the following countries are bound to implement this European Standard: Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.

Introduction

Wavelength dispersive X-ray fluorescence spectrometry (XRF) has been used for several decades as an important analytical tool for production analysis. XRF is characterised by its speed and high precision over a wide concentration range and as the XRF-method in most cases is used as a relative method, the limitations are often connected to the quality of the calibration samples. The technique is well established and most of the physical fundamentals are well known.

This guideline is intended to be used for the analysis of copper and copper alloys but it may also be applied to other materials.

1 Scope

This European Standard provides guidance on the concepts and procedures for the calibration and analysis of copper and copper alloys by wavelength dispersive X-ray fluorescence spectrometry.

2 Principle

An appropriately prepared test sample is irradiated by an X-ray beam of high energy. The secondary X-rays produced are dispersed by means of crystals and the intensities are measured by detectors at selected characteristic wavelengths. Concentrations of elements are determined by relating the measured intensities of test samples to calibration curves prepared from reference materials.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

3.1

reference material

RM

material, sufficiently homogeneous and stable with respect to one or more specified properties which has been established to be fit for its intended use in a measurement process

[SOURCE: ISO GUIDE 30:1992/Amd.1:2008, definition 2.1]

3.2

certified reference material

CRM

reference material characterized by a metrologically valid procedure for one or more specified properties, accompanied by a certificate, that provides the value of the specified property, its associated uncertainty, and a statement of metrological traceability

[SOURCE: ISO GUIDE 30:1992/Amd.1:2008, definition 2.2]

3.3

test sample

representative quantity of material for testing purposes

3.4

calibration samples

series of certified reference materials or if not available, reference materials used for calibration

3.5

drift control samples

series of homogeneous materials that contain all the elements which have been calibrated and that cover the low, mid and high points of the calibration range for each element, used to detect variations over time in these points

Note 1 to entry: Drift control samples can also be used for statistical process control (SPC) of the instrument.

3.6

recalibration samples

samples at both low and high points in the calibration ranges used to recalibrate the spectrometer

Note 1 to entry: These samples are measured during the calibration procedure and the intensities obtained are stored in the computer according to the manufacturer's instructions.

SS-EN 15063-1:2014 (E)

Note 2 to entry: No chemical analyses are necessary, but the homogeneity of these samples should be carefully evaluated.

**3.7
calibration**

process to establish the curve(s) by measuring and calculating the best fit of net intensities for elemental concentrations of a number of calibration samples

**3.8
recalibration**

adjusting instrumental output to conform to the calibration

Note 1 to entry: To compensate for day to day instrumental variation, a set of recalibration samples are measured at the minimum low concentration and at a high concentration for each element (two-points recalibration). The measured intensities are compared to the initial measured intensities stored during the calibration procedure and the recalibration coefficients are calculated. Calibration constants are not changed.

**3.9
reference measurements**

measurements carried out to determine intensities for reference materials

Note 1 to entry: Initial intensities for the reference materials are stored during the calibration procedure and the intensities are updated to compensate for day to day variations.

**3.10
spectral background**

background caused by radiation energy of a wavelength corrected for its position in the spectrum, but not directly related to the desired observation

Note 1 to entry: For a spectral line, spectral background may consist of other lines, bands or continuous radiation.

**3.11
background equivalent concentration**

concentration of analyte, which, when it is excited, provides a net intensity equal to the spectral background

Note 1 to entry: See Annex A.

**3.12
limit of detection**

minimum concentration at which the signal generated by a given element can be positively recognised with a specified confidence level above any background signals

Note 1 to entry: See Annex A.

**3.13
lower limit of detection**

calculated minimum concentration based on counting statistical error at which the signal generated by a given element can be positively recognised, with a specified confidence level, above any background signals

Note 1 to entry: See Annex A.

**3.14
limit of quantification**

smallest concentration that can be determined with a specified confidence level related to the limit of detection by a factor dependent on the method

Note 1 to entry: See Annex A.

3.15

sensitivity

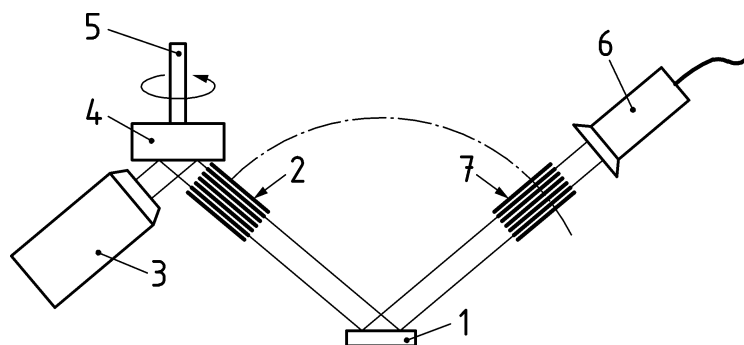
rate of change of signal with change in concentration

Note 1 to entry: See Annex A. Sensitivity is expressed as counts per second percent, and derived by difference in signals between a sample with a high concentration and one with a low concentration divided by the difference in concentrations.

4 Instrumentation

4.1 Principles of X-ray fluorescence spectrometers

The principles of two different X-ray fluorescence spectrometer concepts are shown in Figures 1 and 2. Each detail is described in the following sub-clauses.



Key

- | | | | |
|---|--------------------|---|----------------------|
| 1 | Crystal | 5 | Spinner |
| 2 | Primary collimator | 6 | Counter |
| 3 | X-ray tube | 7 | Secondary collimator |
| 4 | Test sample | | |

Figure 1 — Plane crystal spectrometer geometry, used in sequential instruments